



J | A | C | S
JOURNAL OF THE AMERICAN CHEMICAL SOCIETY

J. Am. Chem. Soc., 1997, 119(51), 12659-12660, DOI: [10.1021/ja972054n](https://doi.org/10.1021/ja972054n)

Terms & Conditions

Electronic Supporting Information files are available without a subscription to ACS Web Editions. The American Chemical Society holds a copyright ownership interest in any copyrightable Supporting Information. Files available from the ACS website may be downloaded for personal use only. Users are not otherwise permitted to reproduce, republish, redistribute, or sell any Supporting Information from the ACS website, either in whole or in part, in either machine-readable form or any other form without permission from the American Chemical Society. For permission to reproduce, republish and redistribute this material, requesters must process their own requests via the RightsLink permission system. Information about how to use the RightsLink permission system can be found at <http://pubs.acs.org/page/copyright/permissions.html>



ACS Publications

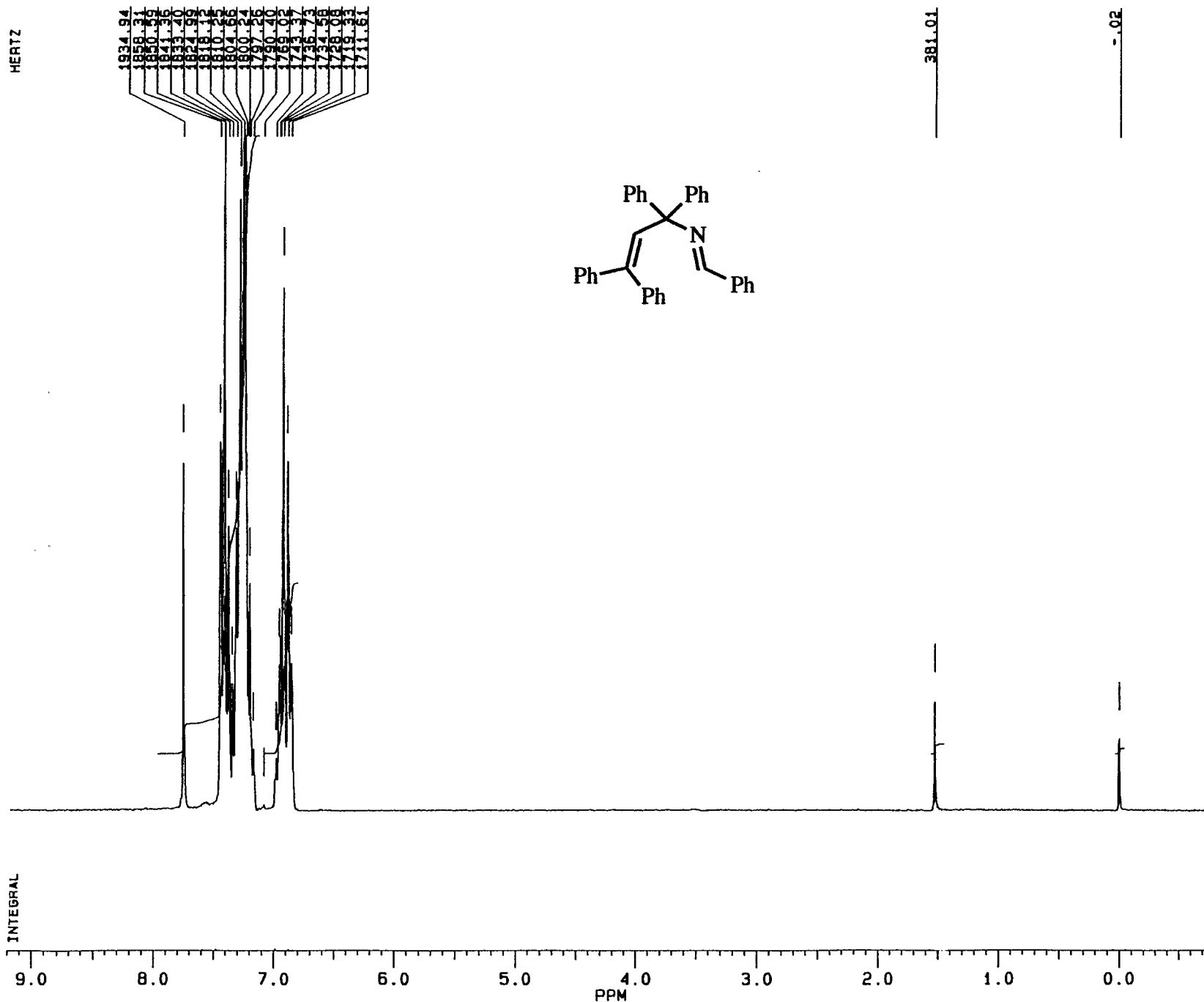
MOST TRUSTED. MOST CITED. MOST READ.

Copyright © 1997 American Chemical Society

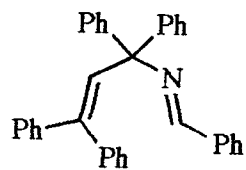
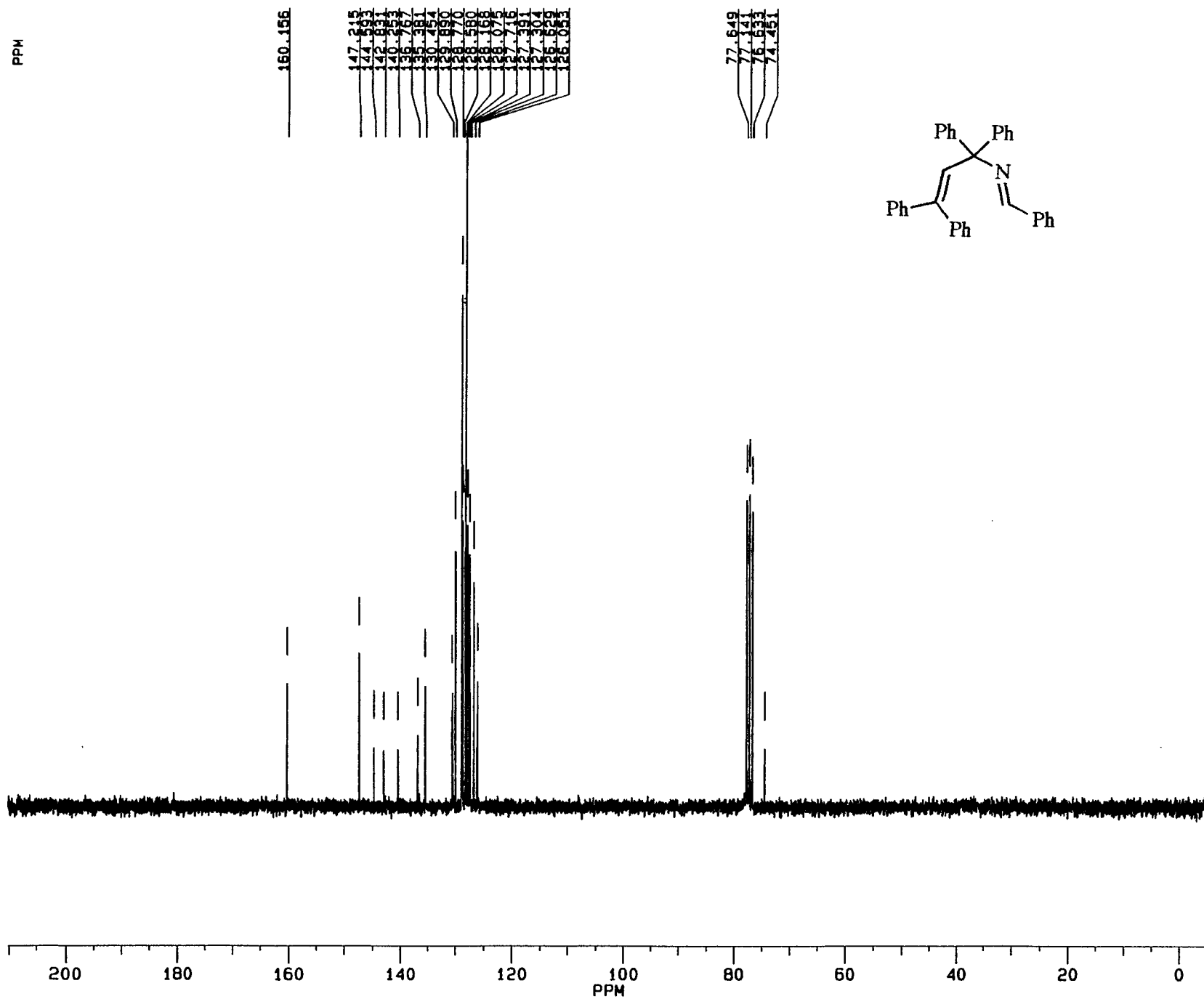
JA972054N

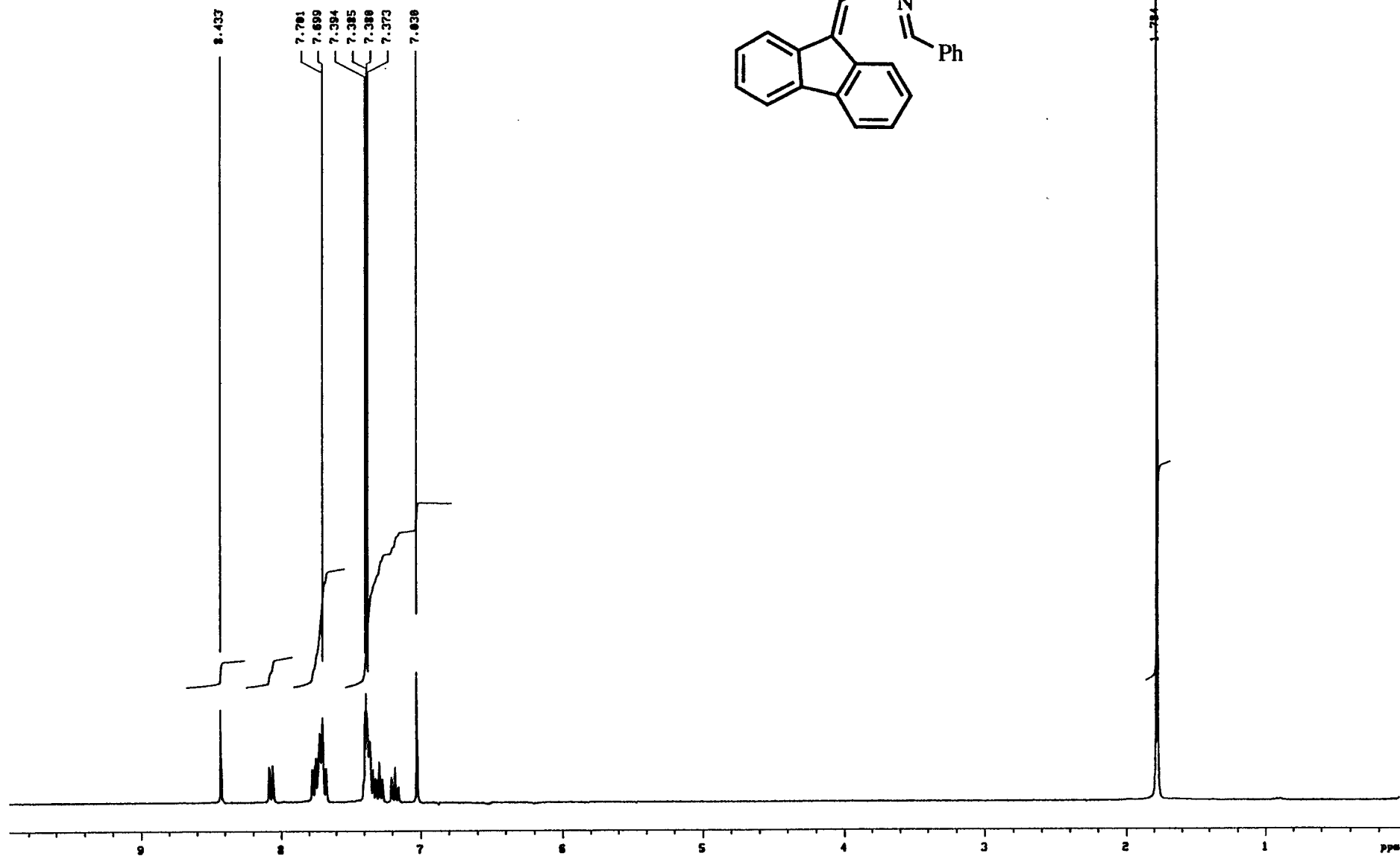
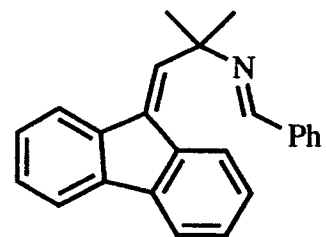
INTEGRAL

HERTZ

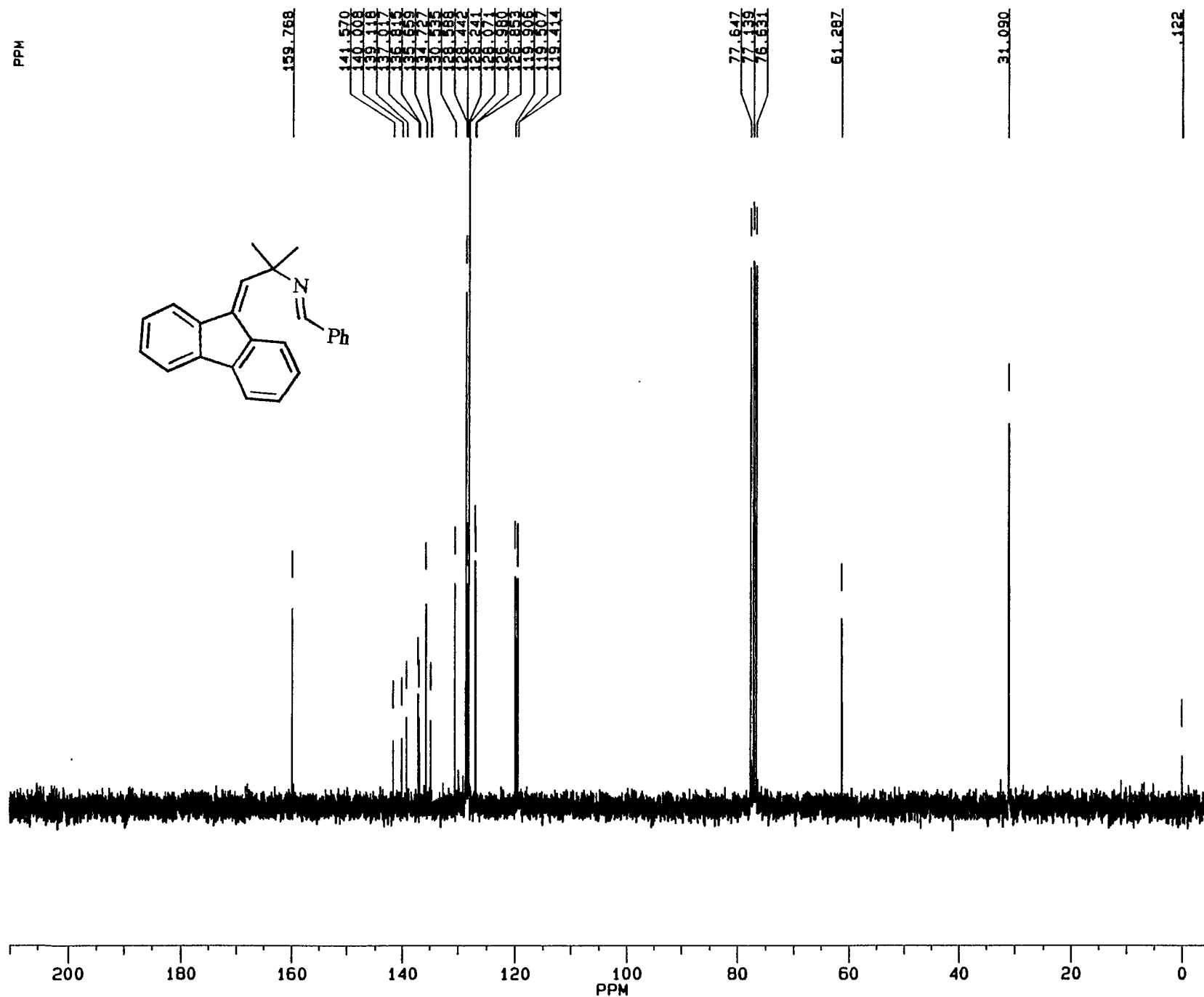
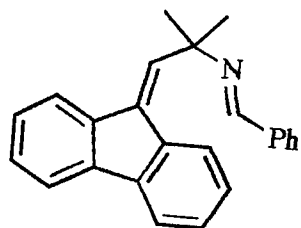


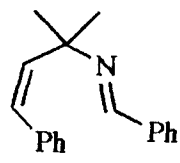
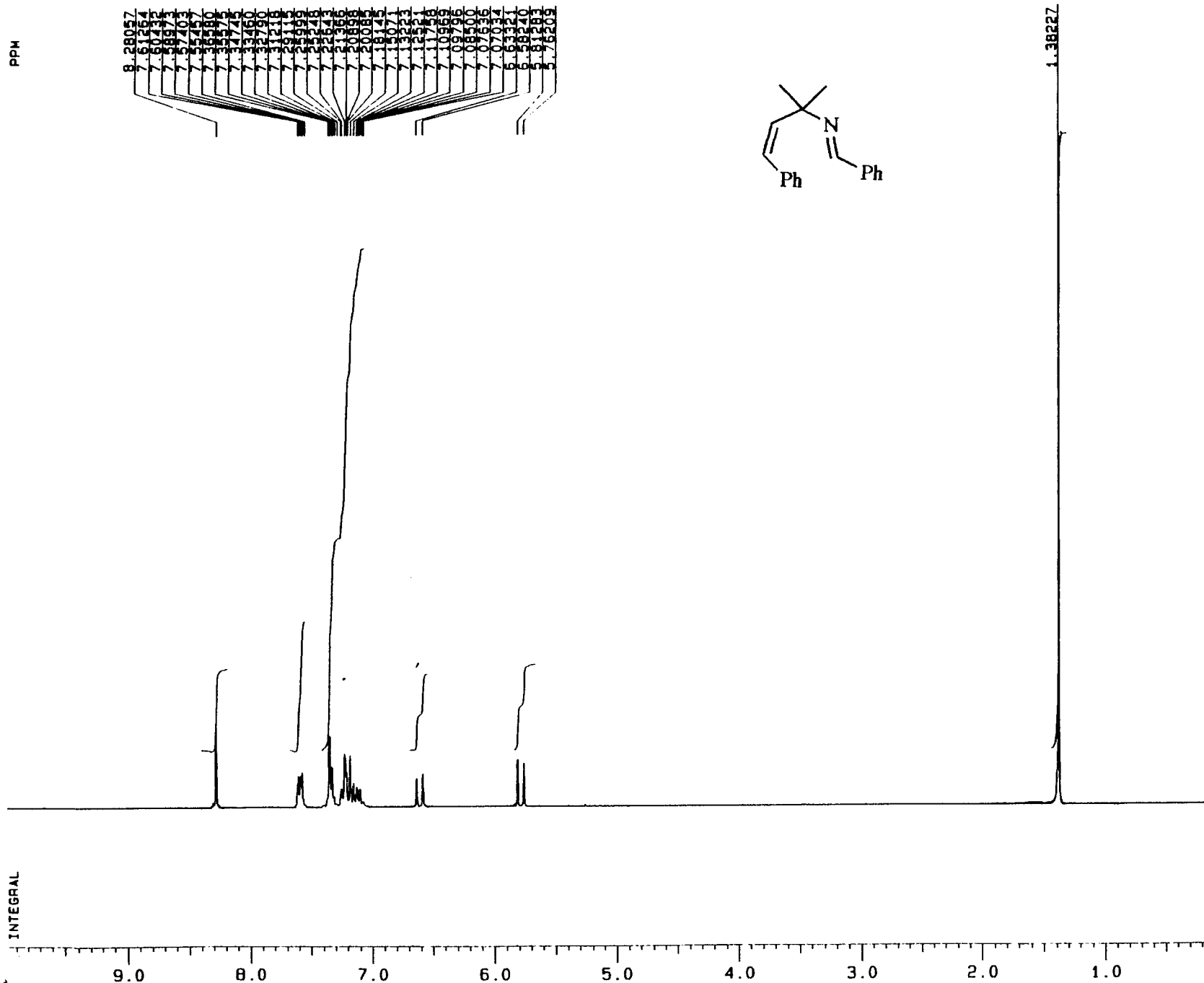
PPM





PPM





PPM

157.731

138.646

137.893

137.871

130.553

130.186

129.262

128.473

128.101

127.785

126.624

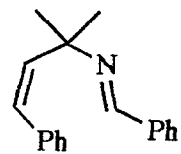
77.576

77.168

76.650

61.806

30.174



200

180

160

140

120

100
PPM

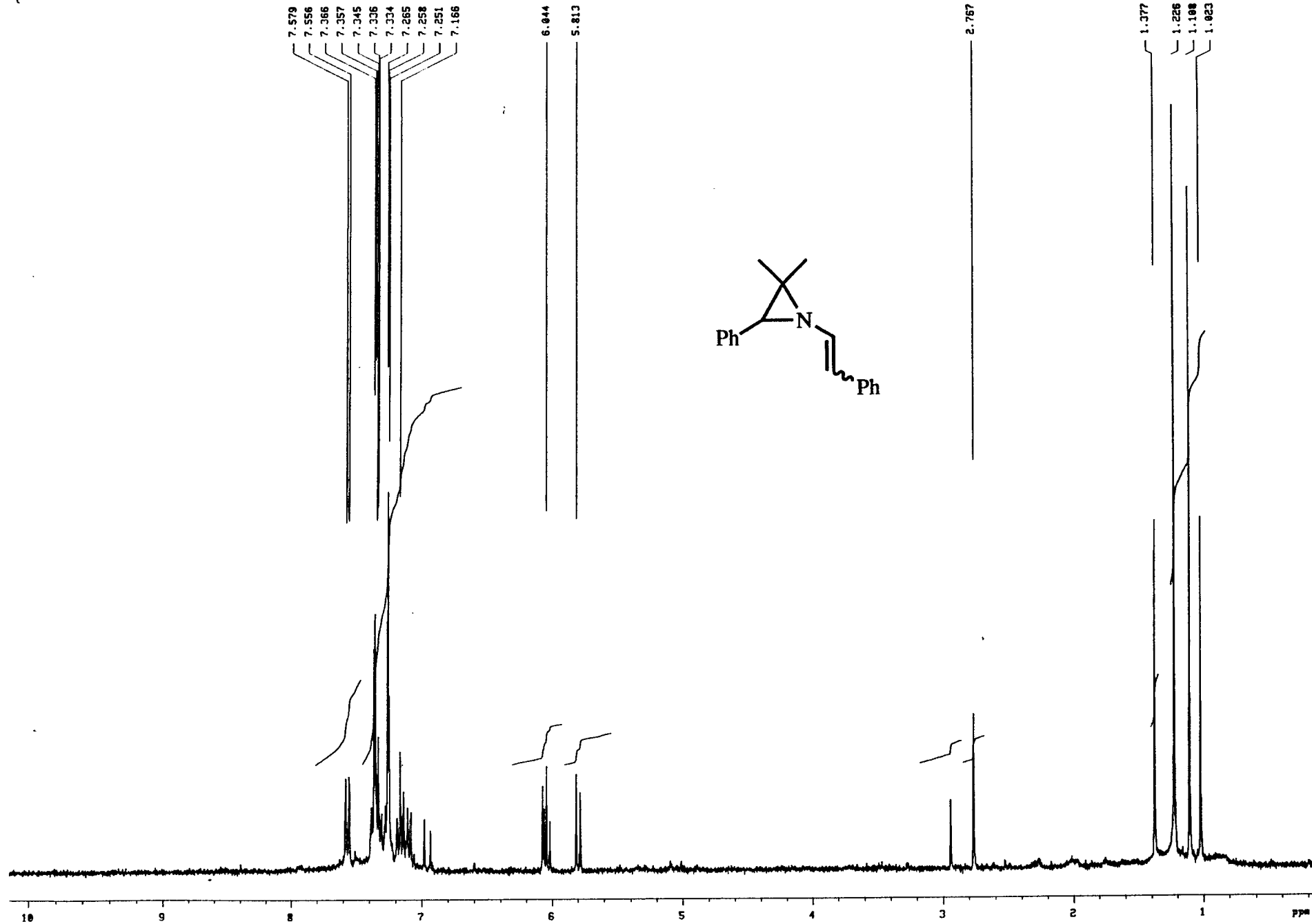
80

60

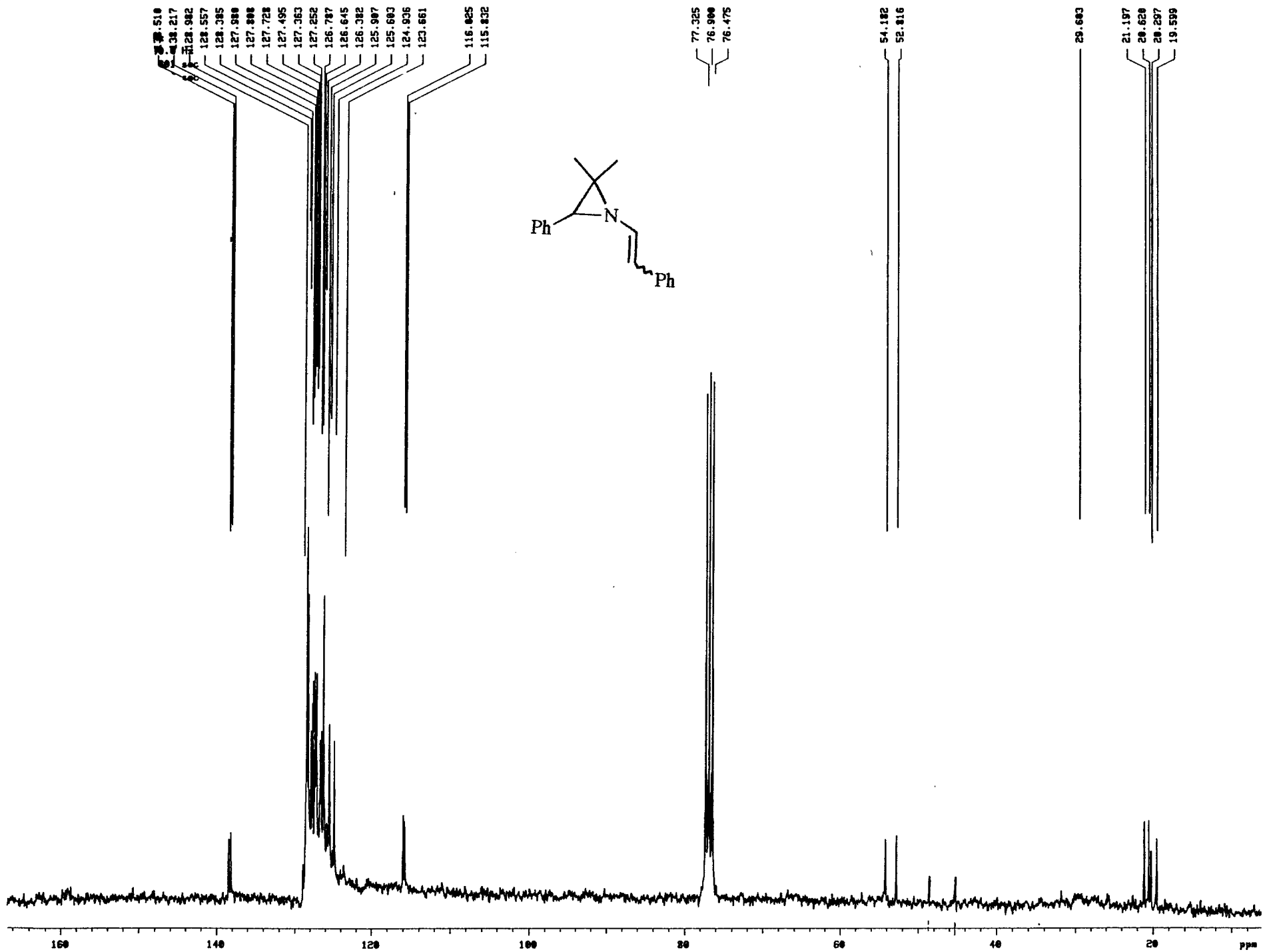
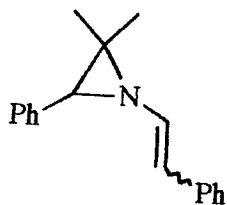
40

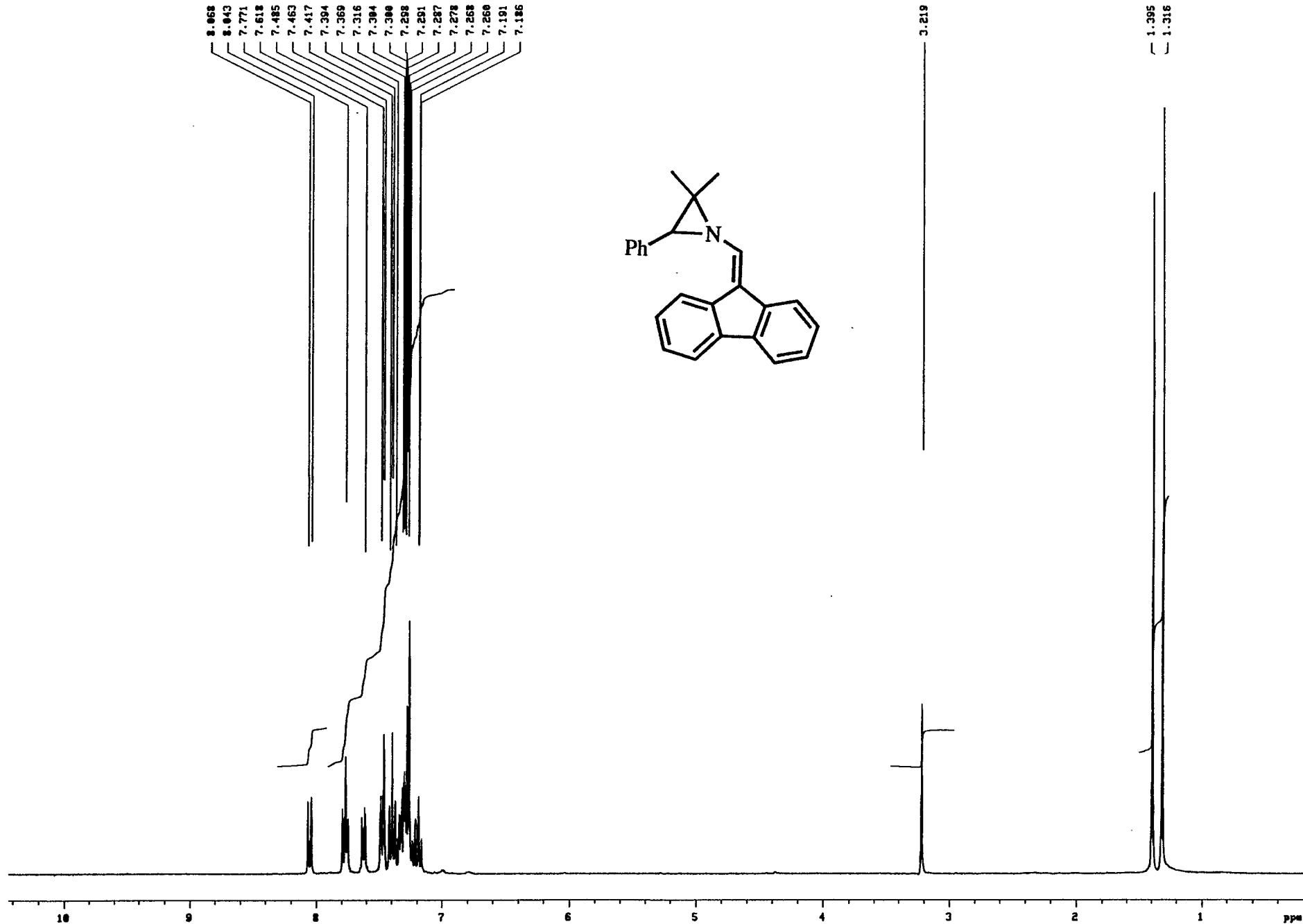
20

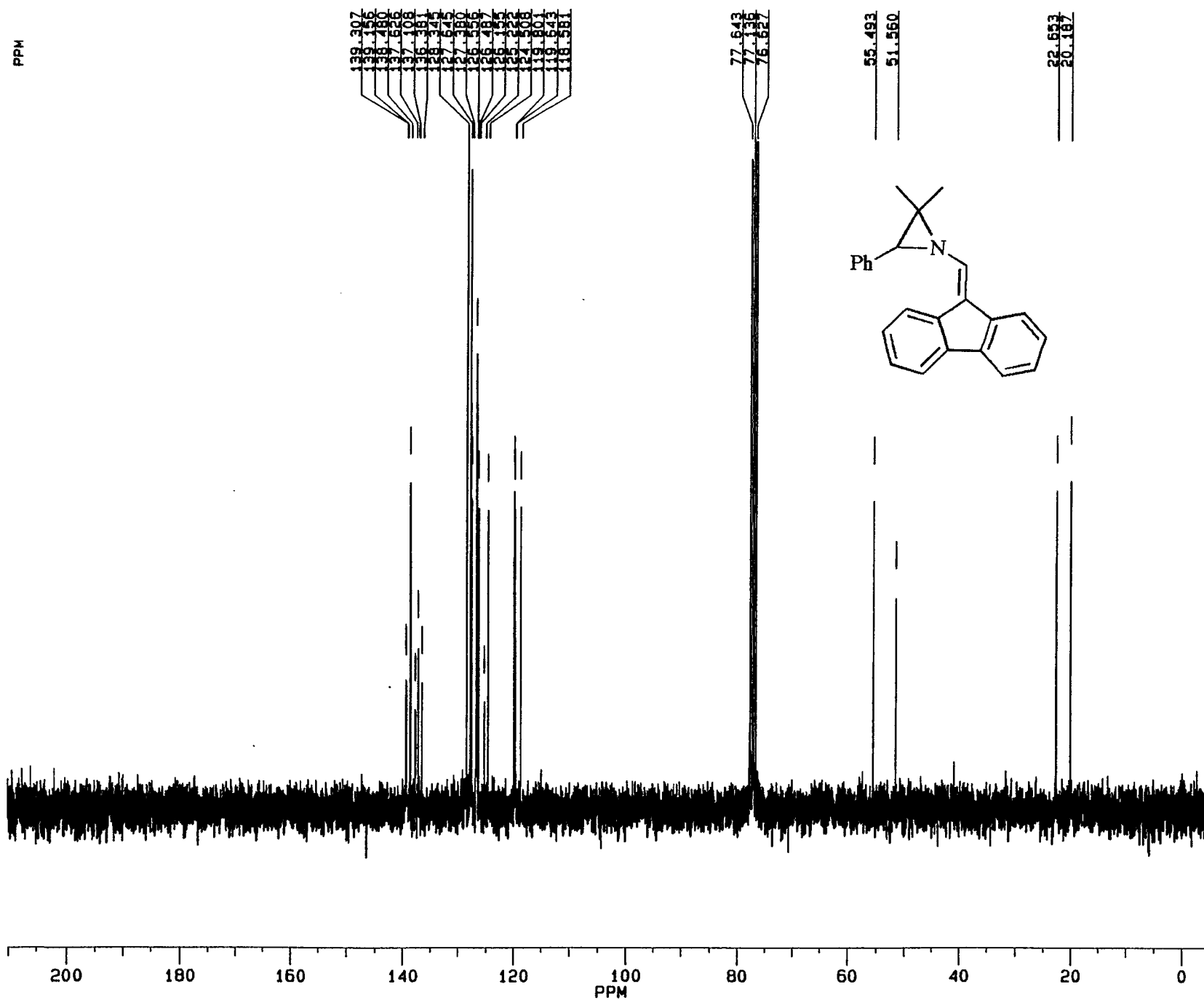
0

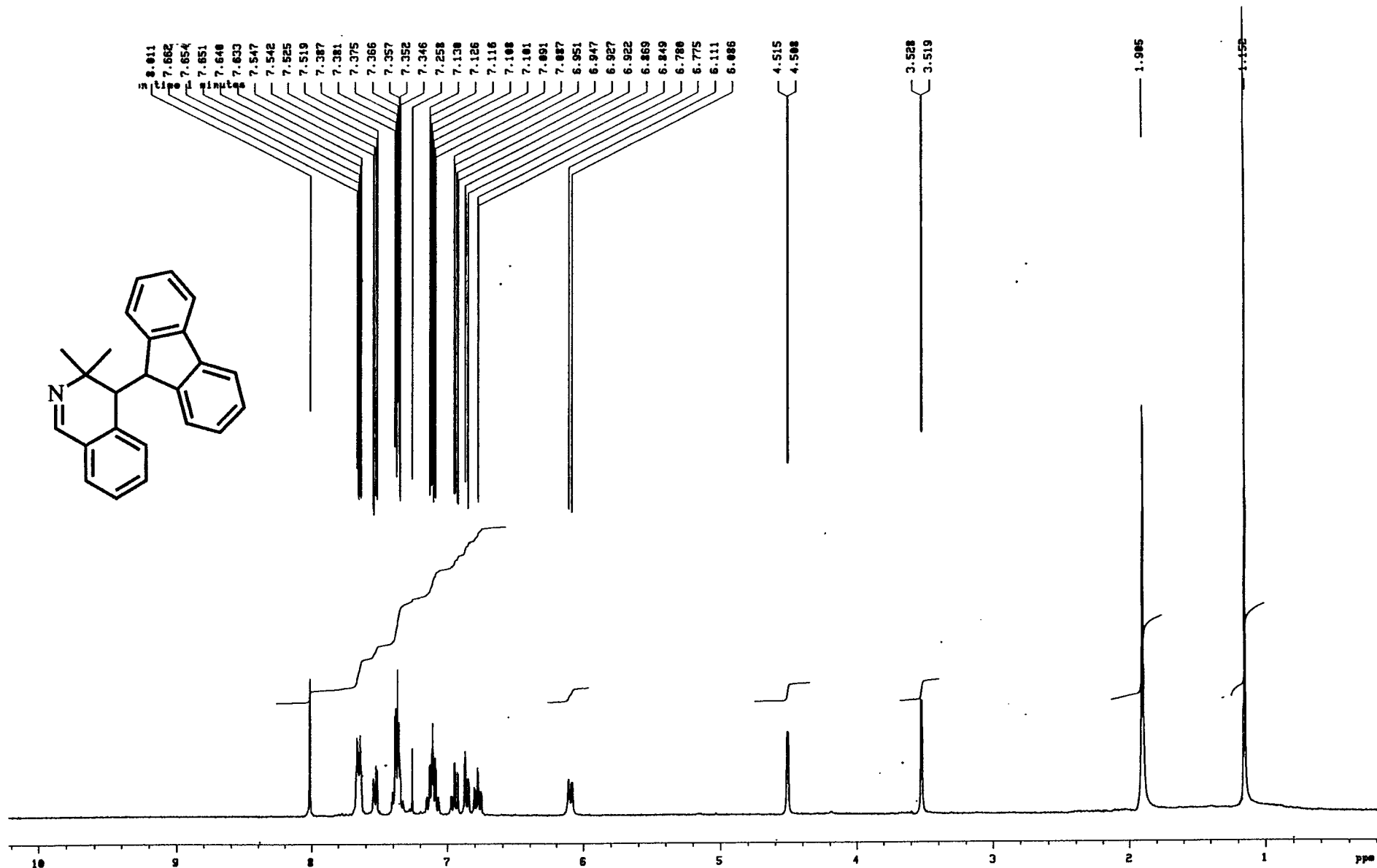
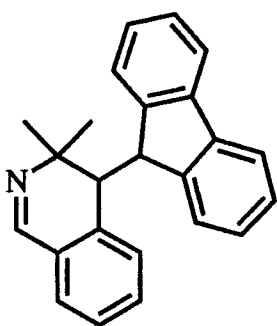


POOR QUALITY ORIGINAL









ppm

159.067

146.650
142.795
141.721
141.518

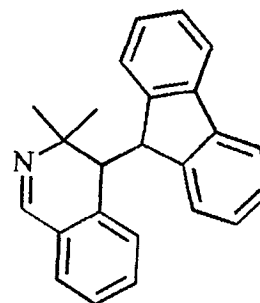
133.994
130.659
128.034
127.505
127.400
127.157
126.771
126.723
126.506
126.186
125.245
124.680
119.541
118.907

77.367
77.146
76.943
76.519

57.212

49.941
48.102

28.987
28.174



200

180

160

140

120

ppm

100

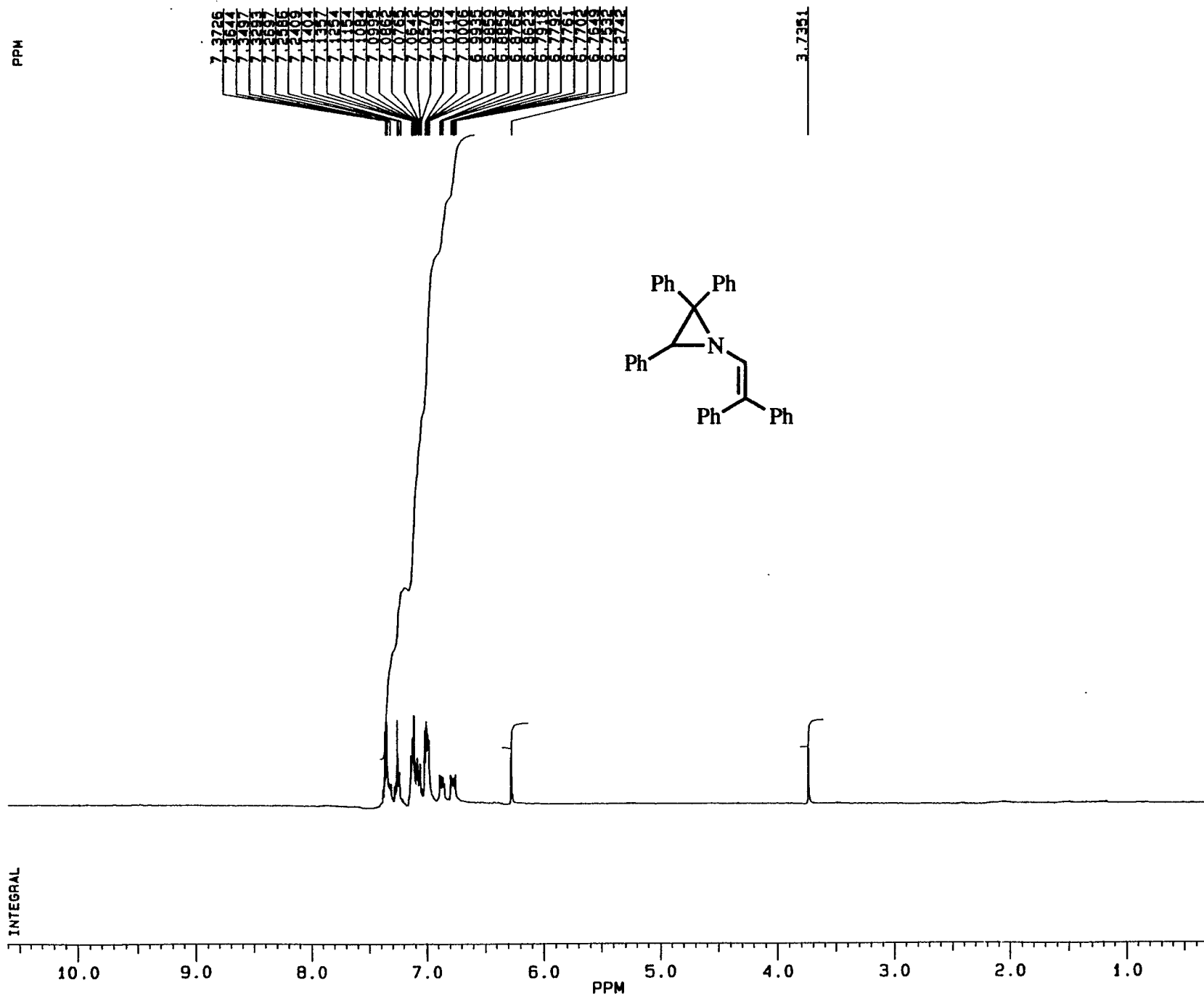
80

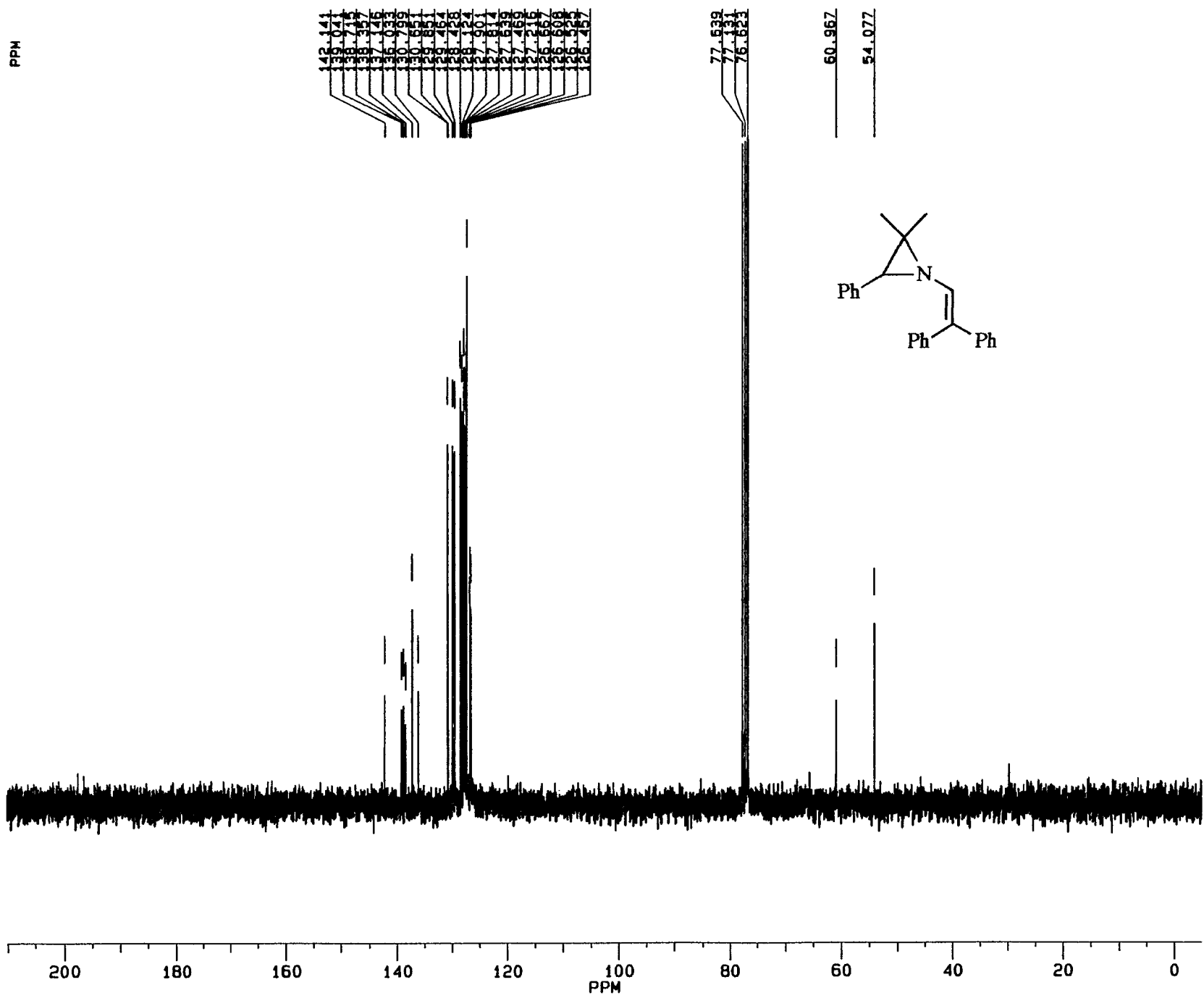
60

40

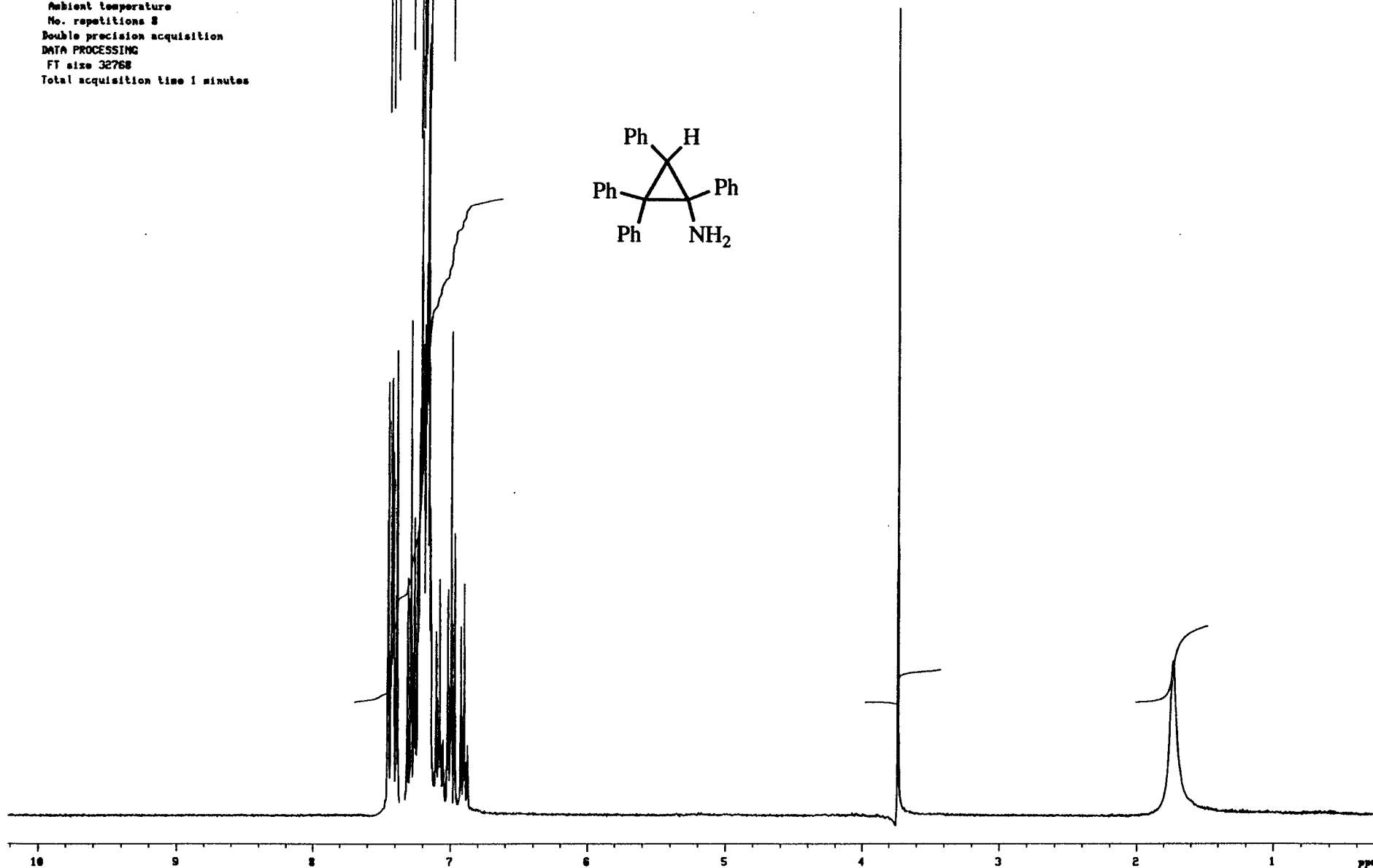
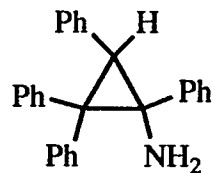
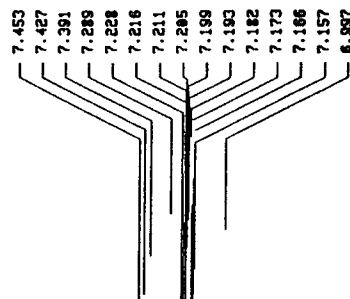
20

0





OBSERVE .il
Frequency 299.949 MHz
Spectral width 5500.6 Hz
Acquisition time 1.501 sec
Relaxation delay 0.000 sec
Pulse width 90.0 degrees
Ambient temperature
No. repetitions 2
Double precision acquisition
DATA PROCESSING
FT size 32768
Total acquisition time 1 minutes



PPM

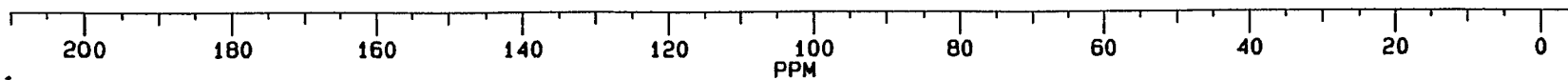
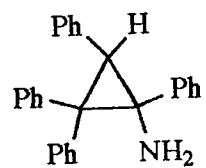
141.517
143.626
138.603
136.759
131.952
130.671
129.293
128.041
127.928
127.724
126.574
126.071
125.897

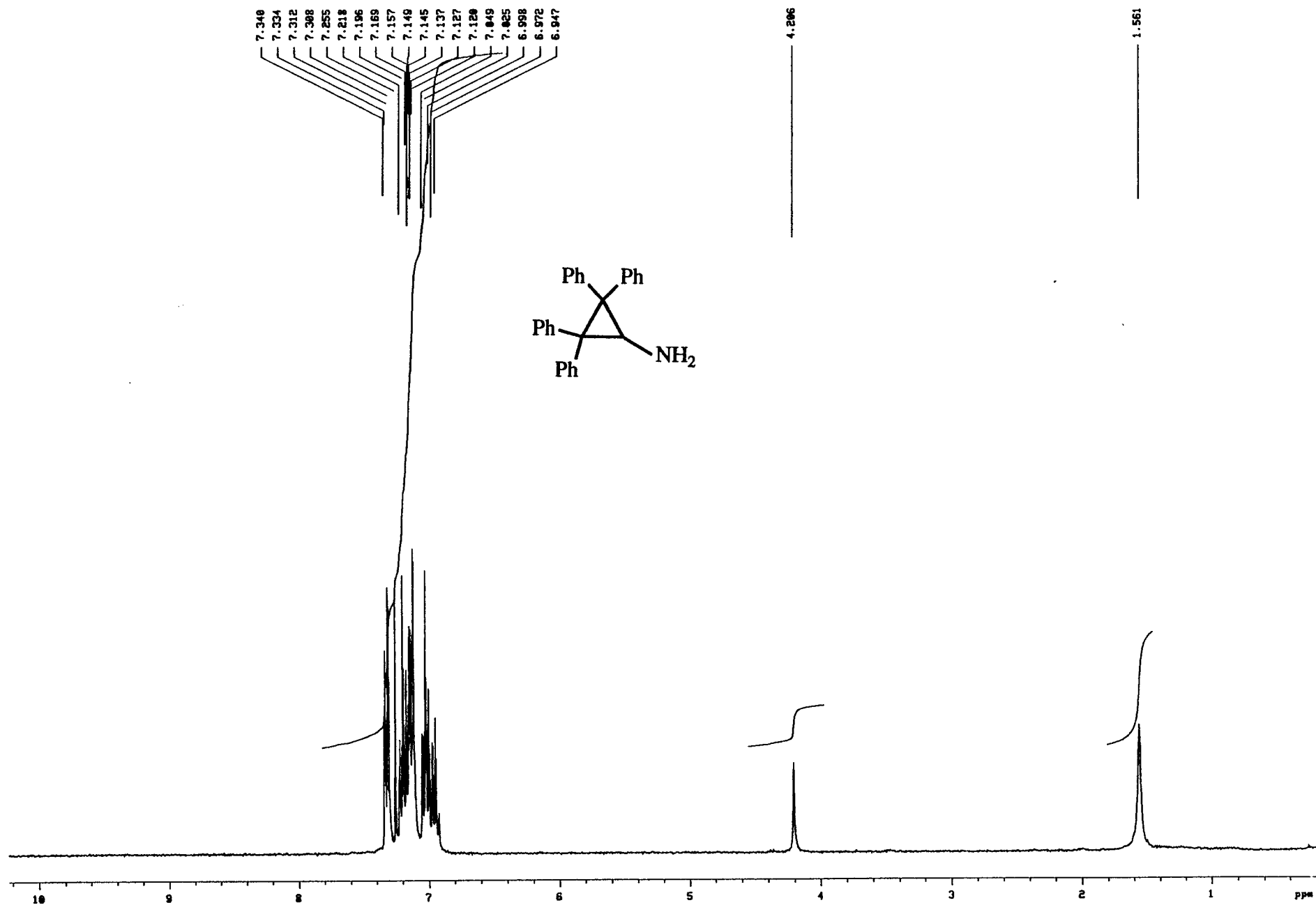
77.648
77.140
76.632

51.977

47.845

38.873





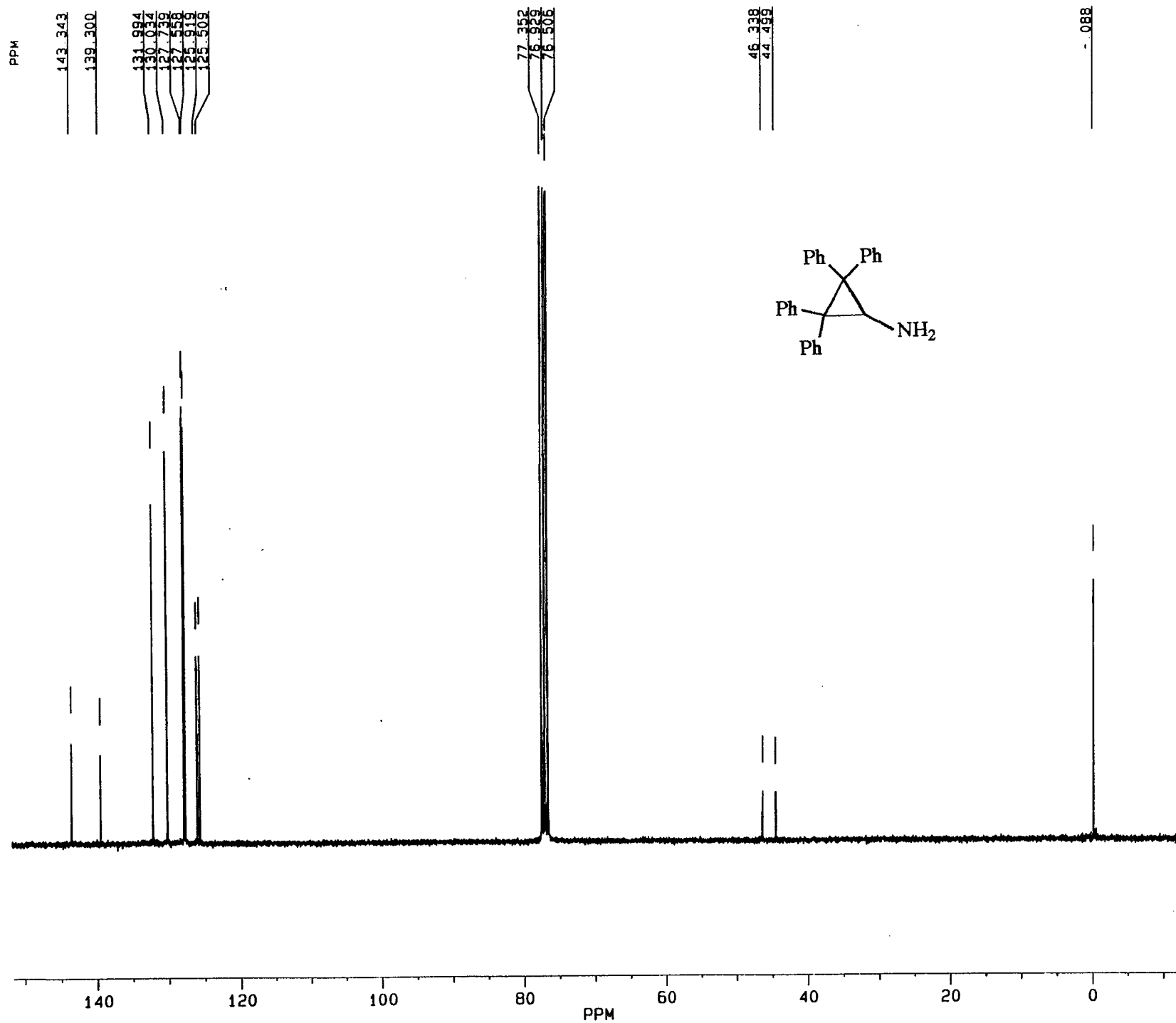


Table . Crystal and Refinement Data for C₃₄NH₂₇

Formula	C ₃₄ NH ₂₇
Mol weight	449.6
Crystal dimensions, mm	0.3x0.3x0.30
Crystal color	colorless
Crystal system	Triclinic
Space group	P(-1) (N. 2)
Cell dimensions	
<i>a</i> , Å	10.843(2)
<i>b</i> , Å	11.223(5)
<i>c</i> , Å	11.654(3)
α, (°)	99.64(2)
β, (°)	96.75(2)
γ, (°)	111.05(3)
<i>Z</i>	2
<i>V</i> , Å ³	1280.2(8)
<i>D</i> _{calcd} , g cm ⁻³	1.17
<i>F</i> (000)	476
temp, K	295
Diffractometer	Enraf-Nonius
Radiation	graphite-monochromated Mo <i>K</i> α (<i>l</i> =0.71069 Å)
Scan technique	<i>ω</i> / <i>2θ</i>
<i>2θ</i> range, °	1-60
Data collected	-15 ≤ <i>h</i> ≤ 15, -15 ≤ <i>k</i> ≤ 15, 0 ≤ <i>l</i> ≤ 16
Unique data	7453
Observed reflections, <i>I</i> > 2σ(<i>I</i>)	3808
<i>R</i> _{int} (%)	1.05
Decay	<1%
Standard reflections	3/75
μ(Mo <i>K</i> α), cm ⁻¹	0.62
Transmission range	0.95-0.98
Weighting scheme	unit
Maximum and average shift/error	0.006, 0.001
Absorption correction range	none
Maximum residual, eÅ ⁻³	0.2
$R = \sum F_o - F_c / \sum F_o $	0.042
$R_w = [\sum w(F_o - F_c)^2 / \sum w F_o ^2]^{1/2}$	0.040
GOF (F)	0.47
Num.Refined Parameters	316
Reflections/parameter ratio	12.05

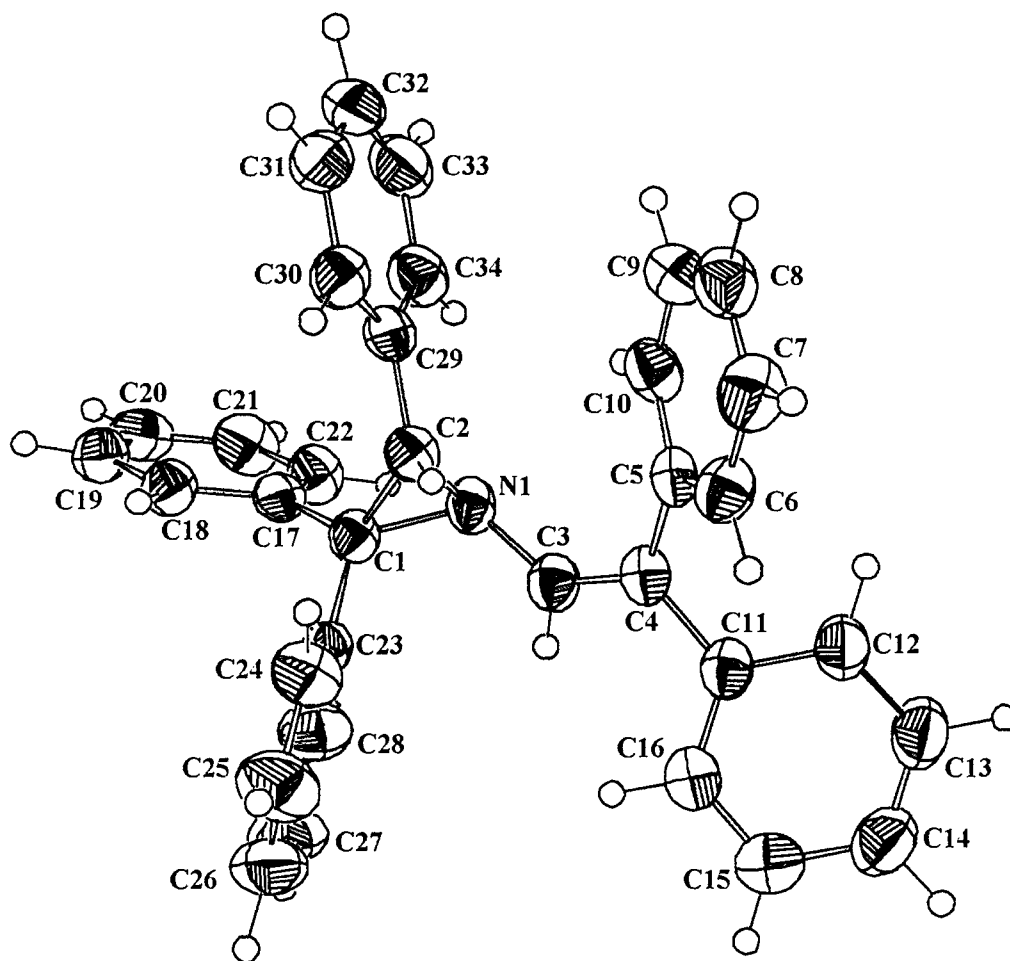


FIGURE *: ORTEP drawing of the molecule of $C_{34}NH_{27}$ with 50% probability ellipsoids. The labeling of hydrogen atoms has been omitted for clarity

EXPERIMENTAL

1. Data Collection

A colorless crystal of prismatic shape and dimension $0.30 \times 0.30 \times 0.30 \text{ mm}^3$ was cut from a larger one grown as described in the experimental section. This crystal was mounted in a Nonius CAD-4 diffractometer to be used for the structure determination. Table I collects the main crystal data and refinement parameters for $\text{C}_{34}\text{NH}_{27}$. A graphite-monochromatic MoK_α ($\lambda = 0.71069 \text{ \AA}$) beam was used in the data collection carried out at room temperature. The unit cell parameters were determined by least-square refinement of the 2θ values of 25 strong well centered reflections in the range $12^\circ < 2\theta < 30^\circ$. The intensities of all 7453 unique reflections (after merging) were measured in the angular range $1^\circ < 2\theta < 60^\circ$ (hkl range $-15, -15, 0$ to $15, 15, 16$) using the $\omega/2\theta$ scan technique. There was no appreciable change in the intensities of three standard reflections periodically monitored. The raw data were corrected for Lorentz and polarization effects and 3808 reflections were considered as observed with $I > 2s(I)$. Scattering factors for neutral atoms were taken from "*International Tables for X-Ray Crystallography*" (1).

2. Structure Determination

The position of non-hydrogen atoms were determined using the direct-methods program MULTAN80 (2). The hydrogen atoms were located by Fourier synthesis. Due to the regular crystal shape and to the low absorption coefficient no absorption correction was applied. Since no trends on ΔF vs. F_o or $\sin\theta/\lambda$ were observed no especial weighting scheme was used, i.e. unit weights were assigned. A final refinement was undertaken with anisotropic thermal motion for the non-hydrogen atoms, while the hydrogen atoms positions were refined but keeping the isotropic thermal parameters constant and equal for all of them. Full-matrix least-squares refinement minimizing $\sum w(|F_o| - |F_c|)^2$ led to agreement factors $R = 0.042$ and $R_w = 0.040$. The maximum and average shift-to-error ratios were 0.006 and 0.001 respectively, while the maximum residual electron density near the C23-C28 phenyl ring was 0.2 e \AA^{-3} . Most of the calculations were carried out with the XRAY80 program (3).

- (1) *International Tables for X-Ray Crystallography*; Kynoch Press; Birmingham, U.K., Vol. IV, p 72., (1974)
- (2) P.Main, S.J.Fiske S.E.Hull, L.Lessinger, G.Germain, J.P.Declercq & M.M.Woolfson, MULTAN80, *A System of Computer Programs for the Automatic Solution of Crystal Structures from X-ray Diffraction Data*. Univ. of York, Engalnd, (1980)
- (3) J.M.Stewart, *The X-RAY80 System*; Computer Science Center, University of Maryland, College Park, MD, (1980).